

PCN# : P276A

Issue Date : Aug. 27, 2012

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to PCNSupport@fairchildsemi.com.

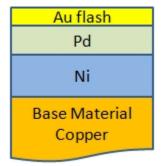
Implementation of change:

Expected First Shipment Date for Changed Product: Nov. 25, 2012

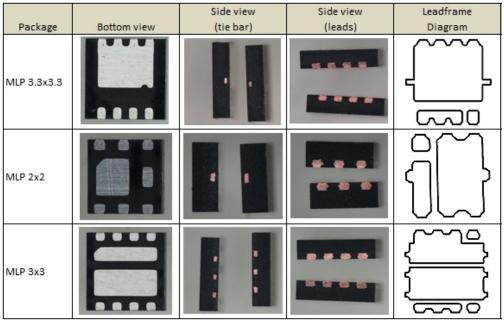
Expected First Date Code of Changed Product :1239

Description of Change (From):

1) Standard leadframe with NiPdAu plating finish.

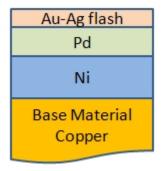


2) No tie bar connected to the corner leads of the package. Package outline view and diagram as shown in the table below.

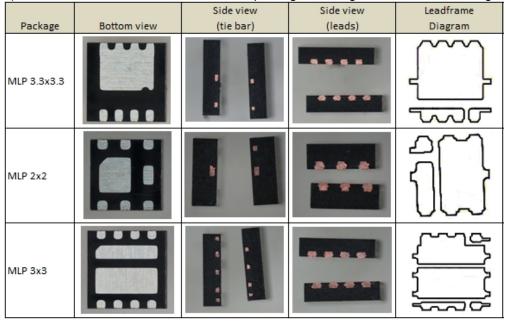


Description of Change (To):

1) Roughened leadframe with NiPdAuAg plating finish.



2) Added tie bar to the corner leads of the package. Package outline view and diagram as shown in the table below.



Reason for Change:

This conversion is to align with Fairchild Penang's consolidation to a similar leadframe process to better utilize equipment. The change will not affect the product electrical specification and solderability. The products incorporating this change may be shipped interchangeably with existing unchanged products.



Affected Product(s):

FDMA291P	FDMA410NZ	FDMA420NZ
FDMA430NZ	FDMA510PZ	FDMA520PZ
FDMA530PZ	FDMA7630	FDMA7632
FDMA7670	FDMA7672	FDMA8878
FDMA8884	FDMA905P	FDMA905P_F130
FDMA910PZ	FDMC0205	FDMC0223
FDMC0223S	FDMC0224	FDMC0225
FDMC0225S	FDMC0310AS	FDMC4435BZ_F126
FDMC4436BZ	FDMC510P	FDMC6676BZ
FDMC6679AZ	FDMC6679AZ_F125	FDMC6680AZ
FDMC6683	FDMC7200	FDMC7200S
FDMC7664	FDMC7672	FDMC7672S_F126
FDMC7672_F125	FDMC7680	FDMC7680MX
FDMC7692S_F126	FDMC8026S	FDMC8200
FDMC8200S	FDMC8200S_SN00246	FDMC8296
FDMC8298	FDMC86102L	FDMC86102LZ
FDMC86240	FDMC86320	FDMC86520L
FDMC8878_F126	FDMC8884_F126	FJMA790
FR011L5J	FR015L3EZ	

Qualification Plan	Device	Package	Process	No. of Lots
Q20110610	FDMC8884 F126	MLDEUC08	PT4 N	1

Test Description:	Condition:	Standard:	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/154
MSL1	260C, 3 cycles	J-STD_020		0/22
Highly Accelerated Stress Test	130C, 85%RH, 5.0V	JESD22-A110	96 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
Bond Pull	9.0g	JESD22-C100		0/5
Bond Shear	90g	AEC-Q100- 001		0/5
Die Shear	0.4g/mil sq	MIL-STD-883- 2019		0/5
Solderability CA	Condition C steam aging (8hrs), Condition A solder Dip (215 for 5 sec)	JESD22-B102		0/11
Solderability CB	Condition C steam aging (8hrs), Condition B solder Dip (245 for 5 sec)	JESD22-B102		0/11

Qualification Plan	Device	Package	Process	No. of Lots
Q20110610	FDMC6683	MLDEUC08	ST3 P	1

Test Description:	Condition:	Standard:	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/154
MSL1	260C, 3 cycles	J-STD_020		0/22
Highly Accelerated Stress Test	130C, 85%RH, 5.0V	JESD22-A110	96 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500	0/77
			cycles	
Bond Pull	9.0g	JESD22-C100		0/5
Bond Shear	90g	AEC-Q100-		0/5
		001		
Die Shear	0.4g/mil sq	MIL-STD-883-		0/5
		2019		
Solderability CA	Condition C steam aging (8hrs),	JESD22-B102		0/11
	Condition A solder Dip (215 for 5 sec)			
Solderability CB	Condition C steam aging (8hrs),	JESD22-B102		0/11
	Condition B solder Dip (245 for 5 sec)			

Qualification Plan	Device	Package	Process	No. of Lots
Q20110610	FDMA510PZ	MLDEBC06	ST3 PZ	1

Test Description:	Condition:	Standard:	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/154
MSL1	260C, 3 cycles	J-STD_020		0/22
Highly Accelerated Stress Test	130C, 85%RH, 5.0V	JESD22-A110	96 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77
Bond Pull	9.0g	JESD22-C100		0/5
Bond Shear	90g	AEC-Q100- 001		0/5
Die Shear	0.4g/mil sq	MIL-STD-883- 2019		0/5
Solderability CA	Condition C steam aging (8hrs), Condition A solder Dip (215 for 5 sec)	JESD22-B102		0/11
Solderability CB	Condition C steam aging (8hrs), Condition B solder Dip (245 for 5 sec)	JESD22-B102		0/11

Qualification Plan	Device	Package	Process	No. of Lots
Q20110610	FDMC8200S	MLDEDCX8	PT7 N	1

Test Description:	Condition:	Standard:	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/154
MSL1	260C, 3 cycles	J-STD_020		0/22
Highly Accelerated Stress Test	130C, 85%RH, 5.0V	JESD22-A110	96 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500	0/77
			cycles	
Bond Pull	9.0g	JESD22-C100		0/5
Bond Shear	90g	AEC-Q100-		0/5
		001		
Die Shear	0.4g/mil sq	MIL-STD-883-		0/5
		2019		
Solderability CA	Condition C steam aging (8hrs),	JESD22-B102		0/11
	Condition A solder Dip (215 for 5 sec)			
Solderability CB	Condition C steam aging (8hrs),	JESD22-B102		0/11
	Condition B solder Dip (245 for 5 sec)			